

FCC TEST REPORT

APPLICANT

Beijing LLVision Technology Co., Itd

PRODUCT NAME

Smart Glass Host

MODEL NAME

GLXSS Pro

TRADE NAME

GLXSS

BRAND NAME

GLXSS

STANDARD(S)

47 CFR Part 15 Subpart B

TEST DATE

2017-01-20 to 2017-02-06

ISSUE DATE

2017-02-07

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

NOTE: This document is issued by MORLAB, the test report shall not be reproduced except in full without prior written permission of the company. The test results apply only to the particular sample(s) tested and to the specific tests carried out which is available on request for validation and information confirmed at our website.

MORLAB GROUP

FL1-3, Building A, FeiYang Science Park, No.8 LongChang Road, Block67, BaoAn District, ShenZhen , GuangDong Province, P. R. China

Tel: 86-755-36698555

Fax: 86-755-36698525



DIRECTORY

1. TECHNICAL INFORMATION	<u>5</u>
1.1. APPLICANT INFORMATION	5
1.2. EQUIPMENT UNDER TEST (EUT) DESCRIPTION	5
2. TEST RESULTS	·····6
2.1. APPLIED REFERENCE DOCUMENTS	6
3. TEST CONDITIONS SETTING	·····7
3.1. Test Mode	
3.2. TEST SETUP AND EQUIPMENTS LIST	8
3.2.1. CONDUCTED EMISSION	8
3.2.2. RADIATED EMISSION	9
4. 47 CFR PART 15B REQUIREMENTS	11
4.1. CONDUCTED EMISSION	11
4.1.1. REQUIREMENT ······	
4.1.2. TEST DESCRIPTION ······	
4.1.3. TEST RESULT	
4.2. RADIATED EMISSION	
4.2.1. REQUIREMENT	
4.2.2. TEST DESCRIPTION	
4.2.3. FREQUENCY RANGE OF MEASUREMENT	
4.2.4. Test Result	··· 15
ANNEX A TEST SETUP PHOTOS	····18
1. MAINS TERMINAL DISTURBANCE VOLTAGE MEASUREMENT	····18
2. CONDUCTED EMISSION MAIN'S PORT SIDE VIEW	····18



3. RADIATED EMISSION (30MHZ-1GHZ)	19
4. RADIATED EMISSION (ABOVE 1GHZ)	19
ANNEX B TEST UNCERTAINTY	20
ANNEX C TESTING LABORATORY INFORMATION	21
1. IDENTIFICATION OF THE RESPONSIBLE TESTING LABORATORY	
2. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION	
3. ACCREDITATION CERTIFICATE	21
4. TEST ENVIRONMENT CONDITIONS	

	Change History				
Issue	Issue Date Reason for change				
1.0	2017-02-07	First edition			



Test Report Declaration

Applicant	Beijing LLVision Technology Co., Itd				
Applicant Address	Room903, Unit A, The Spaces International Center, No.8 Dongdaqiao Road, Chaoyang District, Beijing, P.R. China				
Manufacturer	Huizhou BYD Electronic Company Limited				
Manufacturer Address	Xiang shui River Daya Bay Economic Development Zone Huizhou Guangdong				
Product Name	Smart Glass Host				
Model Name	GLXSS Pro				
Brand Name	GLXSS				
HW Version	B2				
SW Version	G20A_V03.1201				
Test Standards	47 CFR Part 15 Subpart B				
Test Result	PASS				

Tested by		Wu Zhorgwen	
,	_		_

Wu Zhongwen (Test Engineer)

Reviewed by : Xìao Xìong (EMC Manager)

Andy Yeh (Technology Manager)



1. Technical Information

Note: Provided by applicant

1.1. Applicant Information

Company: Beijing LLVision Technology Co., Itd

Address: Room903, Unit A, The Spaces International Center, No.8 Dongdaqiao Road,

Chaoyang District, Beijing, P.R. China

1.2. Equipment under Test (EUT) Description

EUT Type:	Smart Glass Host	ORLA	' B UI	LAB
Serial No:	(N/A, marked #1 by test site)	LAB	ORLA	More
Hardware Version:	B2	MOL	ME	ORL
Software Version:	G20A_V03.1201	AE ORLAN	More	S W

Power supply:	Battery	AB RIA MORE IN AB
MORE AE	Brand Name:	GLXSS
	Model No.:	B18650-2
	Serial No.:	(N/A, marked #1 by test site)
	Capacity:	5800mAh
	Normal Voltage:	3.7V
	Charge Limit:	4.35V
Ancillary Equipment:	AC Adapter (Cha	arger for Battery)
	Brand Name:	GLXSS
	Model No.:	TUUS050200-L00
	Serial No.:	(N/A, marked #1 by test site)
	Rated Input:	~ 100-240V, 50/60Hz, 500mA
	Rated Output:	5.0V=2A

NOTE:

- The EUT is a Smart Glass Host which supports 5.8G SRD, ISM 2.4GHz Bluetooth band, WIFI (802.11a/b/g/n) band and GPS.
- 2. The EUT is equipped with a Type-C port which can be connected to ancillary equipments.
- For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	2017.01.23	PASS
2	15.109	Radiated Emission	2017.01.23	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



3. Test Conditions Setting

3.1. Test Mode

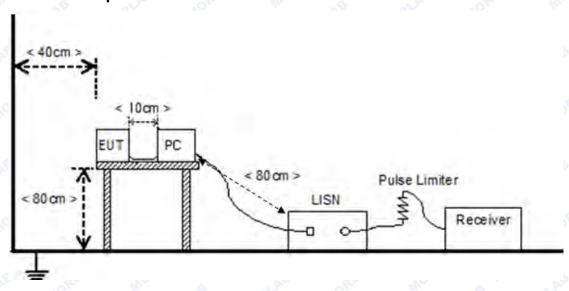
1	The first test mode
	The EUT configuration of the emission tests is EUT + Battery + PC.
	During the measurement, the EUT was connected to a PC via the Type-C port and the
	EUT was charged by the PC. During the measurement, the data is transmitting between the PC and the EUT.
2	The second test mode
	The EUT configuration of the emission tests is EUT + Battery + Adapter.
	During the measurement, the EUT was connected with the Adapter via the Type-C port
	and kept charging by the Adapter, meanwhile, it was kept rated output and working normally.
3	The third test mode
	The EUT configuration of the emission tests is EUT + Battery + Smart glasses. Before the test, the EUT was charged fully. During the measurement, the EUT was
	connected with the Smart glasses, meanwhile, it was kept rated output and working normally.



3.2. Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity in maintained with respect to the impedance characteristics as prescribed in ANSI C63.4-2014 at Clause 4.3.

B. Equipments List:

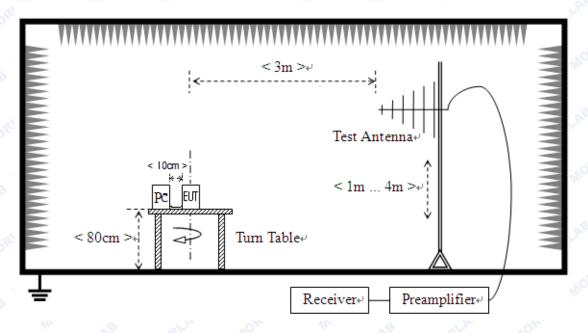
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2016.06.02	2017.06.01
LISN	Schwarzbeck	NSLK 8127	812744	2016.06.02	2017.06.01
Pulse Limiter (20dB)	VTSD	9561D	9537	2016.07.05	2017.07.04



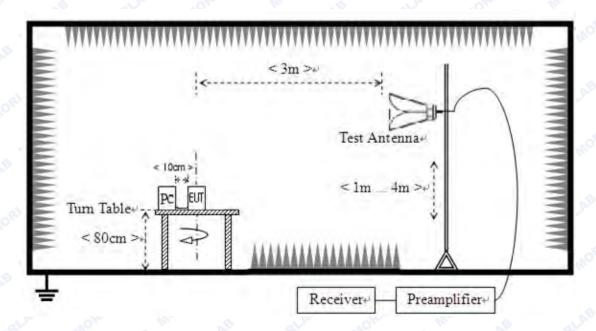
3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



2. For radiated emissions above 1GHz



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of



the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

	44	AV AV				
Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date	
MXE EMI Receiver	Agilent	N9038A	MY54130016	2016.06.03	2017.06.02	
Semi-Anechoic Chamber	Changning	9m*6m*6m	N/A	2016.03.25	2017.03.24	
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2016.12.09	2017.12.08	
Test Antenna - Horn	Schwarzbeck	BBHA9120C	9120C-384	2016.07.05	2017.07.04	
18-26.5GHz pre-Amplifier	MA03	TS-PR18	Rohde&Schwarz	2016.03.02	2017.03.01	
26.5-40GHz pre-Amplifier	C00990	NSP4000-SP 2	Miteq	2016.03.02	2017.03.01	



4. 47 CFR Part 15B Requirements

4.1. Conducted Emission

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu H/50\Omega$ line impedance stabilization network (LISN).

Frequency range	Conducted Limit (dBµV)				
(MHz)	Quasi-peak	Average			
0.15 - 0.50	66 to 56	56 to 46			
0.50 - 5	56	46			
5 - 30	60	50			

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

See section 3.2.1 of this report.

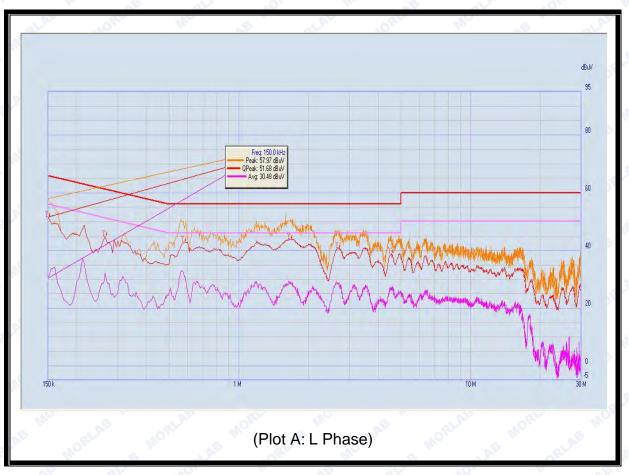
4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

A. Test Plot and Suspicious Points:

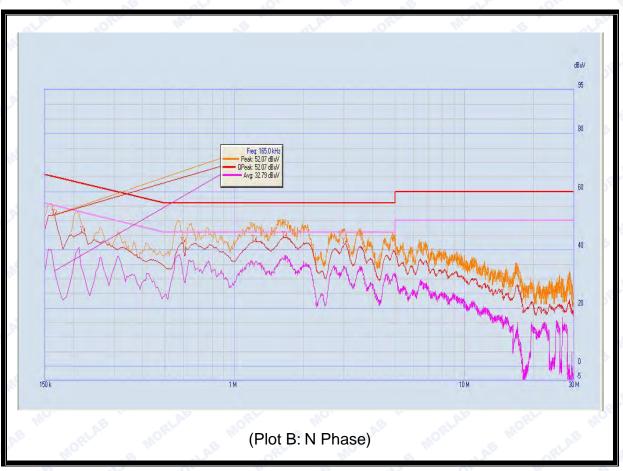






No.	Fre.	Emission Le	vel (dBµV)	Limit (d	dBµV)	Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
A 1	0.15	51.68	30.48	66.00	56.00).	PASS
2	0.265	44.93	32.08	62.71	52.71	ORLA	PASS
3	0.58	42.94	30.93	56.00	46.00	MILLERA	PASS
4	1.66	43.96	28.92	56.00	46.00	Line	PASS
5	2.68	40.81	28.55	56.00	46.00	J.A.B	PASS
6	4.525	38.81	27.00	56.00	46.00	100	PASS





No.	Fre.	Emission Level (dBµV)		Limit (dBµV)		Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.165	52.07	32.79	65.57	55.57	0, 4	PASS
2	0.22	45.96	32.53	64.00	54.00	ORLA	PASS
3	0.60	42.33	31.02	56.00	46.00	S Managard	PASS
4	1.225	43.01	35.24	56.00	46.00	Neutral	PASS
5	1.65	44.37	38.16	56.00	46.00	CLAB	PASS
6	3.02	41.99	33.97	56.00	46.00	Oler W	PASS

Result: Pass



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109 (a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field Strength Limitation	at 3m Measurement Dist
range (MHz)	(μV/m)	(dBµV/m)
30.0 - 88.0	100	20log 100
88.0 - 216.0	150	20log 150
216.0 - 960.0	200	20log 200
Above 960.0	500	20log 500

As shown in FCC section 15.35 (b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level (μV/m).
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of Ld1 = Ld2 * (d2/d1)^{2.}

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as Ld1 = L1 = $30\mu\text{V/m}$ * $(10)^2$ = 100 * $30\mu\text{V/m}$

4.2.2. Test Description

See section 3.2.2 of this report.





4.2.3. Frequency range of measurement

According to 15.33(b) (1), the frequency range of radiated measurement for the EUT is listed in the following table:

Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measure- ment range (MHz)
Below 1.705 1.705–108 108–500 500–1000 Above 1000	30. 1000. 2000. 5000. 5th harmonic of the highest frequency or 40 GHz, whichever is lower.

4.2.4. Test Result

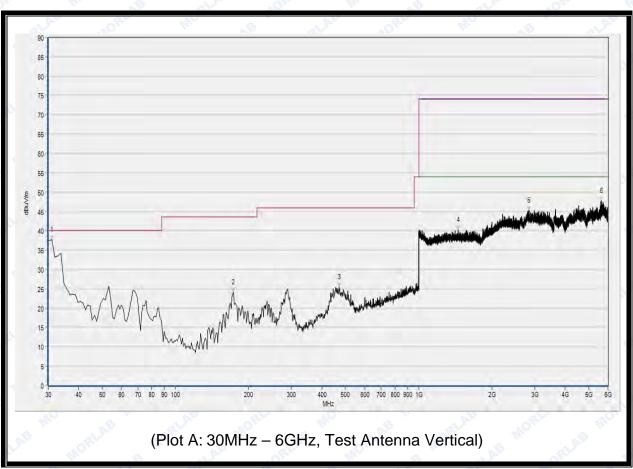
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

The amplitude of emissions (6GHz-30GHz) which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

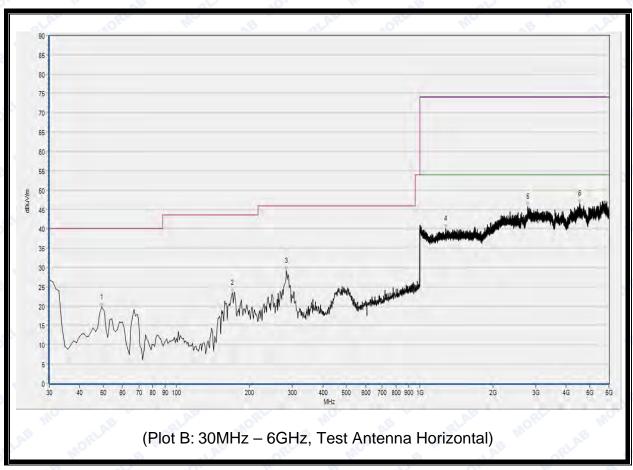
A. Test Plots and Suspicious Points:





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	2LAB	ORL
1	30.970	N.A.	37.69	N.A.	N.A.	40.00	N.A.	V	PASS
2	172.590	N.A.	24.13	N.A.	N.A.	43.50	N.A.	V	PASS
3	470.380	N.A.	25.49	N.A.	N.A.	46.00	N.A.	V	PASS
4	1452.267	40.31	N.A.	34.33	74.00	N.A.	54.00	V	PASS
5	2838.080	45.28	N.A.	39.07	74.00	N.A.	54.00	V	PASS
6	5632.320	47.71	N.A.	41.24	74.00	N.A.	54.00	V	PASS





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	LAB	ORL
10	49.400	N.A.	19.85	N.A.	N.A.	40.00	N.A.	Н	PASS
2	169.680	N.A.	23.48	N.A.	N.A.	43.50	N.A.	Hall	PASS
3	283.170	N.A.	29.14	N.A.	N.A.	46.00	N.A.	Н	PASS
4	1280.000	40.12	N.A.	34.08	74.00	N.A.	54.00	Н 🦪	PASS
5	2784.320	45.80	N.A.	39.64	74.00	N.A.	54.00	Ĥ	PASS
6	4539.200	46.56	N.A.	40.15	74.00	N.A.	54.00	Н	PASS

Result: Pass



Annex A Test Setup photos

1. Mains Terminal Disturbance Voltage Measurement



2. Conducted emission main's port side view

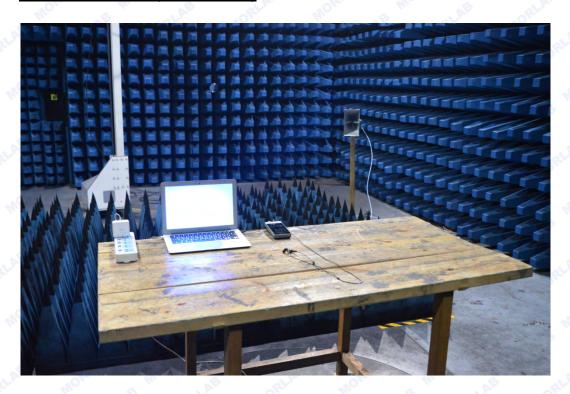




3. Radiated emission (30MHz-1GHz)



4. Radiated emission (Above 1GHz)





Annex B Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB





Annex C <u>Testing Laboratory Information</u>

1. Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

2. Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.
10, 15	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
	Road, Block 67, BaoAn District, ShenZhen, GuangDong
	Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: The FCC registration number is 695796.

(Shenzhen Morlab Communications Technology Co., Ltd.)

4. Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

